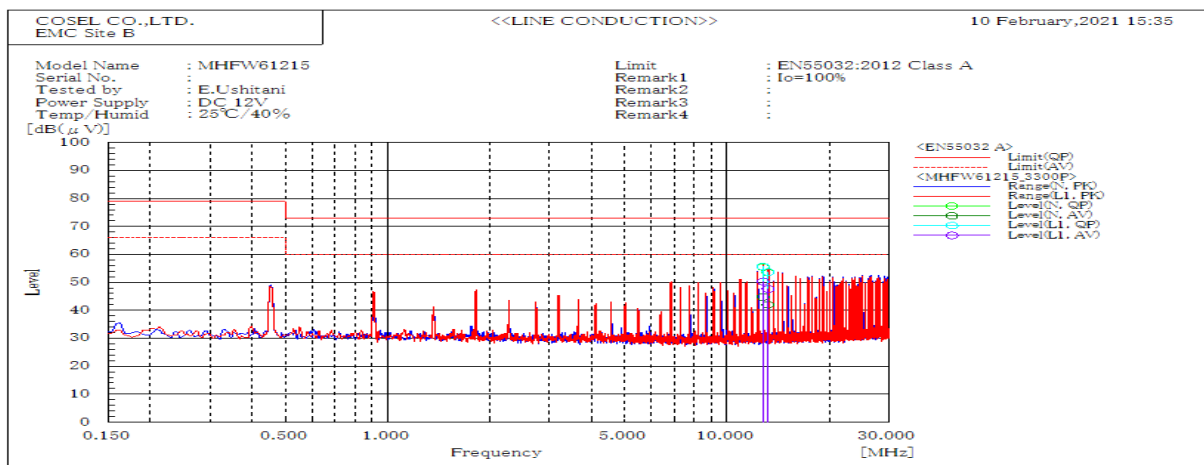
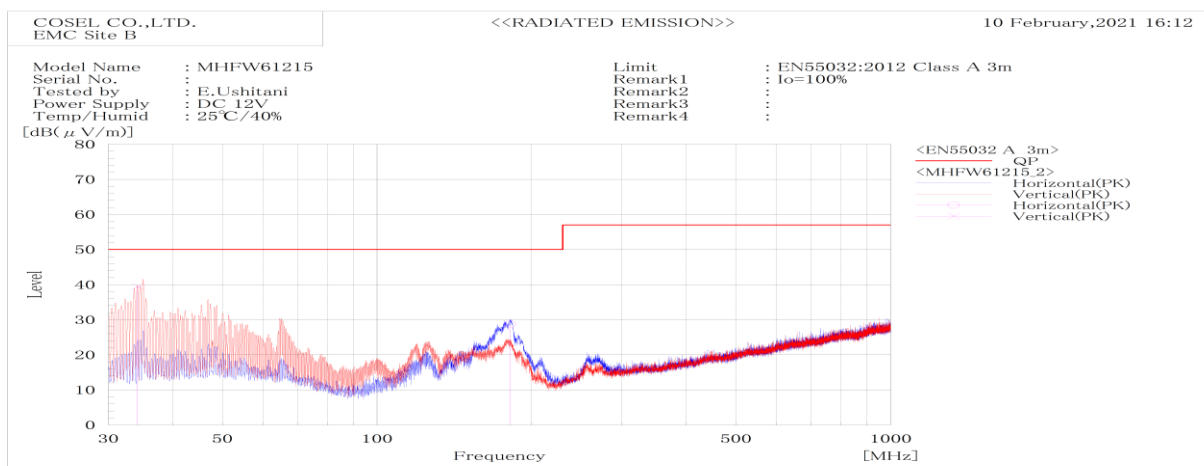


DATA SHEET		Date	05-Nov-21
Model	MHFW61215	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



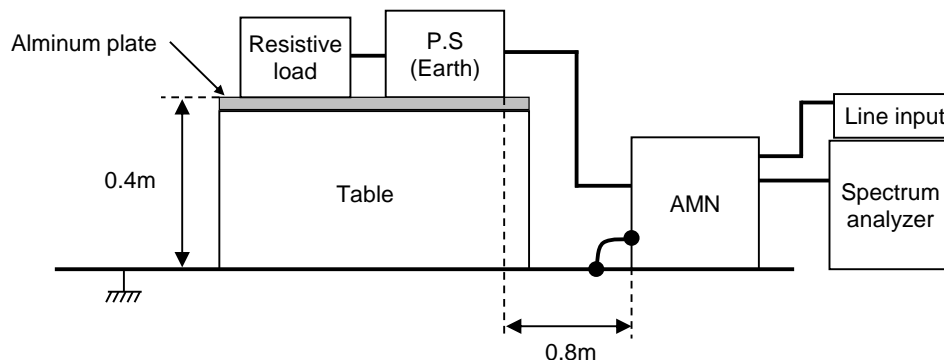
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
12.764	L1	55.7	50.3	73	60	17.3	9.7	Pass	
13.215	L1	53.7	47.6	73	60	19.3	12.4	Pass	
12.764	N	55.5	44.7	73	60	17.5	15.3	Pass	
13.214	N	53.5	42	73	60	19.5	18	Pass	



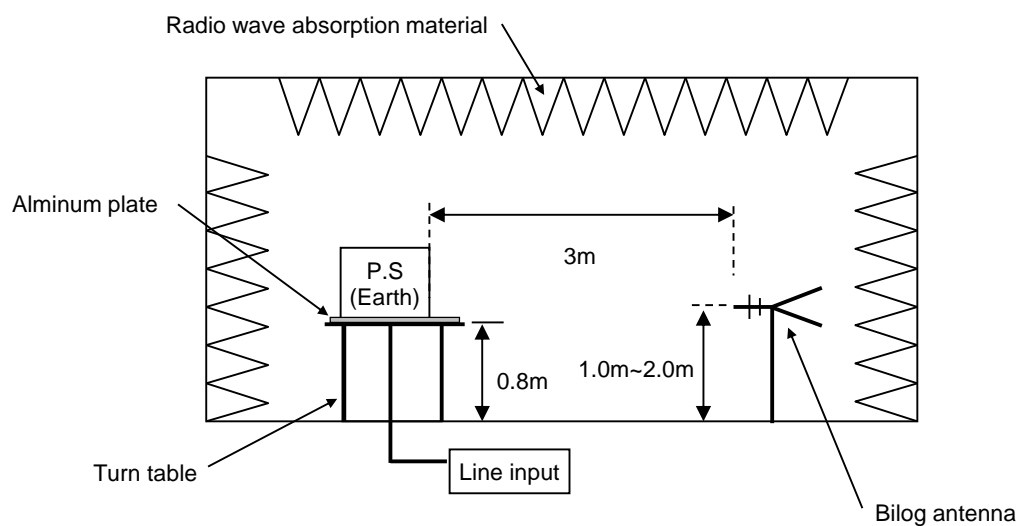
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB				
			QP	QP	QP		cm	deg	
181.456	H	Stable	28.7	50	21.3	Pass	200	343.9	
34.192	V	Stable	39.6	50	10.4	Pass	100	73.9	

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

## 1. Line conduction



## 2. Radiated emission



## Conditions

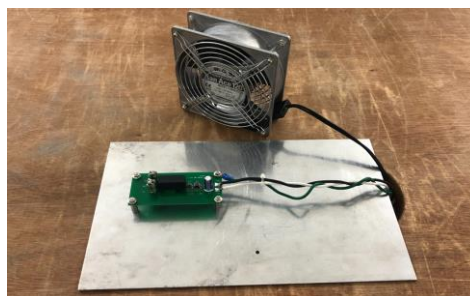
Test : EMI  
Model Name: MHFW6□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

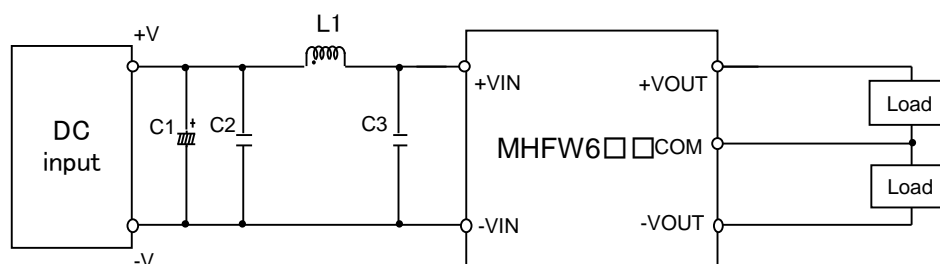


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 $\mu$ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	-
	MHFS648□□	-
C2 :	MHFS612□□	25V 10 $\mu$ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 $\mu$ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 $\mu$ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 $\mu$ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 $\mu$ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 $\mu$ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 $\mu$ H Inductor (LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 $\mu$ H Inductor (LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 $\mu$ H Inductor (LQH5BPN220MT0 MURATA MANUFACTURING)